

A 22 V, 50 m Ω , 3 A Reverse Blocking Integrated Power Switch with VIN Lockout Select and MOSFET Current Monitor Output

General Description

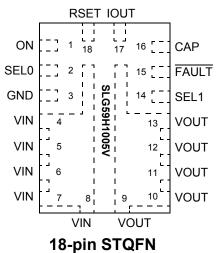
The SLG59H1005V is a high-performance, self-powered 50 m Ω NMOS power switch with back-to-back reverse-current blocking designed for all 4.5 to 22 V power rails up to 3A. Using a proprietary MOSFET design, the SLG59H1005V achieves a stable 50 m Ω RDS_{ON} across a wide input/supply voltage range. Using Silego's proprietary CuFETTM technology, the SLG59H1005V package also exhibits a low thermal resistance for high-current operation.

Designed to operate over a -40°C to 85° C range, the SLG59H1005V is available in a low thermal resistance, RoHS-compliant, 1.6 x 3.0 mm STQFN package.

Features

- Wide Operating Supply Voltage: 4.5 V to 22 V
- Maximum Continuous Switch Current: 3 A
- · Back-to-Back FET Reverse Current Blocking, when OFF
- Internal nFET Power Limiting
- High-performance MOSFET Switch Low RDS_{ON}: 50 m Ω at V_{IN} = 22 V Low Δ RDS_{ON}/ Δ V_{IN}: <0.05 m Ω /V Low Δ RDS_{ON}/ Δ T: <0.06 m Ω /°C
- 4-Level, Pin-programmable V_{IN} Overvoltage Lockout
- Capacitor-adjustable Inrush Current Control
- Two stage Current Limit Protection: Resistor-adjustable Active Current Limit Internal Short-circuit Current limit
- Open Drain FAULT Signaling
- MOSFET Current Analog Output Monitor: 10 µA/A
- Pb-Free / Halogen-Free / RoHS Compliant Packaging

Pin Configuration

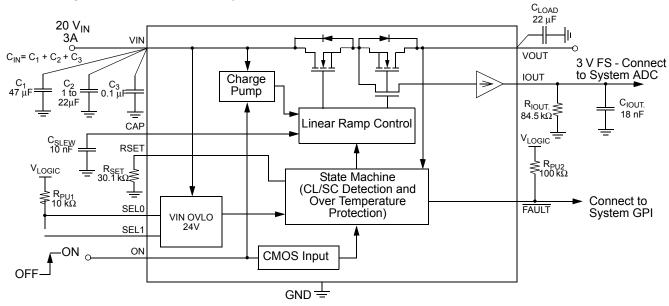


1.6 x 3.0 mm, 0.40mm pitch

```
(Top View)
```

Applications

- Power-Rail Switching
- Multifunction Printers
- Large-format Copiers
- Telecommunications Equipment
- High-performance Computing
 4.5 V and 22 V Point-of-Load Power Distribution
- Motor Drives



Block Diagram and a 20 V / 3 A Typical Application Circuit



Pin Description

Pin #	Pin Name	Туре	Pin Description
1	ON	Input	A low-to-high transition on this pin initiates the operation of the SLG59H1005V's state machine. ON is an asserted HIGH, level-sensitive CMOS input with $V_{IL} < 0.3 V$ and $V_{IH} > 0.85 V$. As the ON pin input circuit does not have an internal pull-down resistor, connect this pin to a general-purpose output (GPO) of a microcontroller, an application processor, or a system controller – do not allow this pin to be open-circuited.
2	SEL0	Input	As level-sensitive, CMOS inputs with V _{IL} < 0.3 V and V _{IH} > 1.65 V, the SEL0 (LSB) and the SEL1 (MSB) pins select one of four V _{IN} overvoltage lockout thresholds. Please see the Applications Section for additional information and the Electrical Characteristics table for the V _{IN} overvoltage thresholds. A logic LOW on either pin is achieved by connecting the pin of interest to GND; a logic HIGH on either pin is achieved by connecting a 10 k Ω external resistor from the pin in question to the system's local logic supply.
3	GND	GND	Pin 3 is the main ground connection for the SLG59H1005V's internal charge pump, its gate drive and current-limit circuits as well as its internal state machine. Therefore, use a short, stout connection from Pin 3 to the system's analog or power plane.
4-8	VIN	MOSFET	VIN supplies the power for the operation of the SLG59H1005V, its internal control circuitry, and the drain terminal of the back-to-back, reverse-blocking nFET power switch. With 5 pins fused together at VIN, connect a 47 μ F (or larger) low-ESR capacitor from this pin to ground. Capacitors used at VIN should be rated at 50 V or higher.
9-13	VOUT	MOSFET	Drain terminal of n-channel MOSFET (5 pins fused for VOUT). Connect a 22 μ F (or larger) low-ESR capacitor from this pin to ground. Capacitors used at VOUT should be rated at 50 V or higher.
14	SEL1	Input	Please see SEL0 Pin Description above
15	FAULT	Output	An open drain output, FAULT is asserted within TFAULT _{LOW} when a V _{IN} overvoltage, a current-limit, or an over-temperature condition is detected. FAULT is deasserted within TFAULT _{HIGH} when the fault condition is removed. Connect an 100 k Ω external resistor from the FAULT pin to local system logic supply.
16	CAP	Output	A low-ESR, stable dielectric, ceramic surface-mount capacitor connected from CAP pin to GND sets the V _{OUT} slew rate and overall turn-on time of the SLG59H1005V. For best performance, the range for C _{SLEW} values are 10 nF \leq C _{SLEW} \leq 20 nF – please see typical characteristics for additional information. Capacitors used at the CAP pin should be rated at 10 V or higher. Please consult Applications Section on how to select C _{SLEW} based on V _{OUT} slew rate and loading conditions.
17	IOUT	Output	IOUT is the SLG59H1005V's power MOSFET load current monitor output. As an analog output current, this signal when applied to a ground-reference resistor generates a voltage proportional to the current through the n-channel MOSFET. The I _{OUT} transfer characteristic is typically 10 μ A/A with a voltage compliance range of 0.5 V \leq V _{IOUT} \leq 4 V. Optimal I _{OUT} linearity is exhibited for 0.5 A \leq I _{DS} \leq 3 A. In addition, it is recommended to bypass the IOUT pin to GND with a 0.18 nF capacitor.
18	RSET	Input	A 1%-tolerance, metal-film resistor between 30 k Ω and 95 k Ω sets the SLG59H1005V's active current limit. A 95 k Ω resistor sets the SLG59H1005V's active current limit to 1 A and a 30 k Ω resistor sets the active current limit to 3 A.

Ordering Information

Part Number	Туре	Production Flow
SLG59H1005V	STQFN 18L FC	Industrial, -40 °C to 85 °C
SLG59H1005VTR	STQFN 18L FC (Tape and Reel)	Industrial, -40 °C to 85 °C



Absolute Maximum Ratings

Parameter	Description	Conditions	Min.	Тур.	Max.	Unit
		Continuous	-0.3		30	V
V _{IN} to GND	Power Switch Input Voltage to GND	Maximum pulsed V _{IN} , pulse width <0.1s			32	V
V _{OUT} to GND	Power Switch Output Voltage to GND		-0.3		VIN	V
ON, SEL[1,0], CAP, RSET, IOUT, and FAULT to GND	ON, SEL[1,0], CAP, RSET, IOUT, and FAULT Pin Voltages to GND		-0.3		7	V
T _S	Storage Temperature		-65		150	°C
ESD _{HBM}	ESD Protection	Human Body Model	2000			V
ESD _{CDM}	ESD Protection	Charged Device Model	500			V
MSL	Moisture Sensitivity Level		1			
θ_{JA}	Thermal Resistance	1.6 x 3.0 mm 18L STQFN; De- termined with the device mount- ed onto a 1 in ² , 1 oz. copper pad of FR-4 material		40		°C/W
T _{J,MAX}	Maximum Junction Temperature			150		°C
MOSFET IDS _{CONT}	Continuous Current from VIN to VOUT	T _J < 150°C			4	А
MOSFET IDS _{PEAK}	Peak Current from VIN to VOUT	Maximum pulsed switch current, pulse width < 1 ms, 1% duty cy- cle			5	A
only and function	r than those listed under "Absolute Maximi onal operation of the device at these or a not implied. Exposure to absolute maximu	any other conditions above those ind	icated in t	he operati	onal section	

Electrical Characteristics

 $4.5 \text{ V} \le \text{V}_{IN} \le 22 \text{ V}; \text{ C}_{IN} = 47 \text{ }\mu\text{F}, \text{ }T_{\text{A}} = -40^{\circ}\text{C} \text{ to } 85^{\circ}\text{C}, \text{ unless otherwise noted. Typical values are at } \text{T}_{\text{A}} = 25^{\circ}\text{C}$

Parameter	Description	Conditions	Min.	Тур.	Max.	Unit
V _{IN}	Operating Input Voltage		4.5		22	V
		V _{IN} ↑; SEL[1,0] = [0,0]	5.6	6	6.3	V
M		V _{IN} ↑; SEL[1,0] = [0,1]	10.2	10.8	11.4	V
V _{IN(OVLO)}	V _{IN} Overvoltage Lockout Threshold	V _{IN} ↑; SEL[1,0] = [1,0]	13.5	14.4	22 6 6.3 10.8 11.4	V
		V _{IN} ↑; SEL[1,0] = [1,1]	22.6	24	25.2	V
IN(OVLOHYST)	V _{IN} Overvoltage Lockout Hysteresis			2		%
V _{IN(UVLO)}	V _{IN} Undervoltage Lockout Threshold	V _{IN} ↓	3	3.2	3.4	V
Ι _Q	Quiescent Supply Current	ON = HIGH; I _{DS} = 0 A		0.5	0.6	mA
I _{SHDN}	OFF Mode Supply Current	ON = LOW; I _{DS} = 0 A		1	3	μA
RDS _{ON}	ON Resistance	$T_A = 25^{\circ}C;$ $I_{DS} = 0.1 A$		50	52	mΩ
RD3 _{ON}	UN RESISTANCE	T _A = 85°C; I _{DS} = 0.1 A		65	68	mΩ



Electrical Characteristics (continued)

 $4.5 \text{ V} \le \text{V}_{\text{IN}} \le 22 \text{ V}; \text{ C}_{\text{IN}} = 47 \text{ }\mu\text{F}, \text{ T}_{\text{A}} = -40^{\circ}\text{C} \text{ to } 85^{\circ}\text{C}, \text{ unless otherwise noted. Typical values are at }\text{T}_{\text{A}} = 25^{\circ}\text{C}$

Parameter	Description	Conditions	Min.	Тур.	Max.	Unit
MOSFET IDS	Current from VIN to VOUT	Continuous			3	Α
IREVERSE	MOSFET Reverse-Leakage Current	V _{IN} = 0 V; V _{OUT} = 22 V; ON = 0 V			3	μA
	Active Current Limit, I _{ACL}	V _{OUT} > 0.5 V; R _{SET} = 30.1 kΩ	3	3.2	3.4	А
I _{LIMIT}	Short-circuit Current Limit, I _{SCL}	V _{OUT} < 0.5 V		0.5		Α
T _{ACL}	Active Current Limit Response Time	R _{SET} = 51.6 kΩ		120		μs
	MOSFET Current Analog Monitor Out-	I _{LOAD} = 1 A	9.3	3 3.2 3.4 0.5 120 1.3 10 10.7 3.5 30 31.5 45 22 0.3 0.5 0.3 0.5 0.7 1.2 Set by External C _{SLEW} 6.5 8 Set by External C _{SLEW} 3.2 3.9	μA	
I _{OUT}	put	I _{LOAD} = 3 A	$\begin{array}{c c c c c c c c c c c c c c c c c c c $	μA		
T _{IOUT}	I _{OUT} Response Time to Change in Main MOSFET Current	C _{IOUT} = 180 pF; Step load 0 to 2.4 A; 0% to 90% I _{OUT}		45		μs
C _{LOAD}	Output Load Capacitance	C _{LOAD} connected from VOUT to GND		22		μF
T _{ON_Delay}		50% ON to 10% V _{OUT} ↑; V _{IN} = 4.5 V; C _{SLEW} = 10 nF; R _{LOAD} = 100 Ω, C _{LOAD} = 10 μF		0.3	0.5	ms
	ON Delay Time	50% ON to 10% V _{OUT} ↑; V _{IN} = 22 V; C _{SLEW} = 10 nF; R _{LOAD} = 100 Ω, C _{LOAD} = 10μF		0.7	1.2	ms
		50% ON to 90% V _{OUT} ↑	Set by	External	C _{SLEW}	ms
T _{Total_ON}	Total Turn-on Time	50% ON to 90% V _{OUT} ↑; V _{IN} = 4.5 V; C _{SLEW} = 10 nF; R _{LOAD} = 100 Ω, C _{LOAD} = 10 μF		1.5	2.1	ms
_		50% ON to 90% V _{OUT} ↑; V _{IN} = 22 V; C _{SLEW} = 10 nF; R _{LOAD} = 100 Ω, C _{LOAD} = 10 μF		6.5	8	ms
		50% ON to 90% V _{OUT} ↑	Set by	External	SLEW V/r	V/ms
V _{OUT(SR)}	V _{OUT} Slew rate	10% to 90% V _{OUT} \uparrow ; V _{IN} = 4.5 to 22 V; C _{SLEW} = 10 nF; R _{LOAD} = 100 Ω, C _{LOAD} = 10 μF	2.7	3.2	3.9	V/ms
T _{OFF_Delay}	OFF Delay Time	50% ON to V _{OUT} \downarrow ; R _{LOAD} = 100 Ω, No C _{LOAD}		15		μs
T _{FALL}	V _{OUT} Fall Time	90% V _{OUT} to 10% V _{OUT} \downarrow ; ON = HIGH-to-LOW; V _{IN} = 4.5 V to 22 V; R _{LOAD} = 100 Ω , No C _{LOAD}	10.4	12.7	14.3	μs
TFAULT	FAULT Assertion Time	Abnormal Step Load Current event to FAULT \downarrow ; I _{ACL} = 1 A; V _{IN} = 22 V; R _{SET} = 95 kΩ; switch in 20 Ω load		80		μs
TFAULT _{HIGH}	FAULT De-assertion Time	Delay to \overline{FAULT} fafter fault condition is removed; $I_{ACL} = 1 A$; $V_{IN} = 22 V$; $R_{SET} = 95 k\Omega$; switch out 20 Ω load		180		μs
FAULT _{VOL}	FAULT Output Low Voltage	I _{FAULT} = 1 mA		0.2		V
ON_V_{IH}	ON Pin Input High Voltage		0.9		5	V
ON_V_{IL}	ON Pin Input Low Voltage		-0.3	0	0.3	V
SEL[1,0]_V _{IH}	SEL[1,0] pins Input High Voltage		1.65		4.5	V

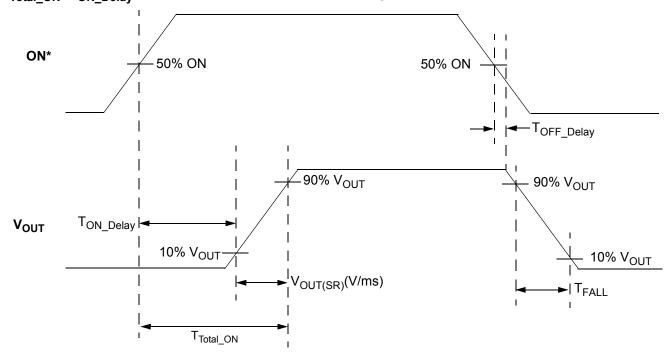


Electrical Characteristics (continued)

 $4.5 \text{ V} \le \text{V}_{\text{IN}} \le 22 \text{ V}; \text{ C}_{\text{IN}} = 47 \text{ }\mu\text{F}, \text{ T}_{\text{A}} = -40^{\circ}\text{C} \text{ to } 85^{\circ}\text{C}, \text{ unless otherwise noted. Typical values are at }\text{T}_{\text{A}} = 25^{\circ}\text{C}$

Parameter	Description	Conditions	Min.	Тур.	Max.	Unit
SEL[1,0]_V _{IL}	SEL[1,0] pins Input Low Voltage		-0.3		0.3	V
I _{ON(Leakage)}	ON Pin Leakage Current	$1V \le ON \le 5V$ or $ON = GND$			1	μA
THERMON	Thermal Protection Shutdown Threshold			125		°C
THERMOFF	Thermal Protection Restart Threshold			100		°C
Notes: 1. Refer to typ	bical Timing Parameter vs. C _{SLEW} perform	ance charts for additional information wh	en available	9.		

$T_{Total_ON},\,T_{ON_Delay}$ and Slew Rate Measurement Timing Details

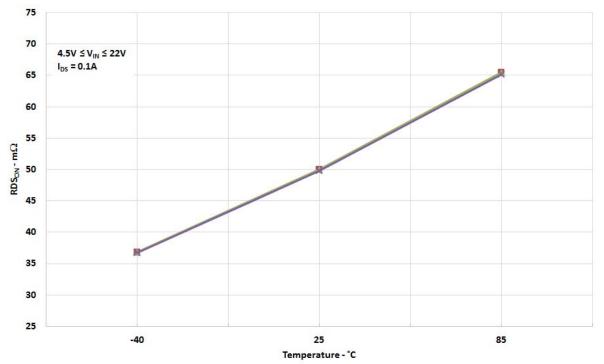


* Rise and Fall times of the ON signal are 100 ns

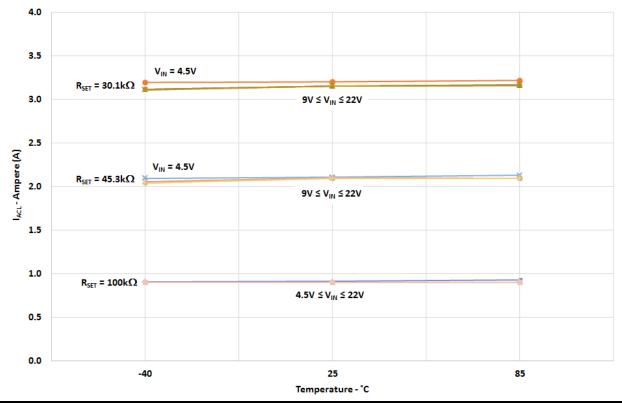


Typical Performance Characteristics

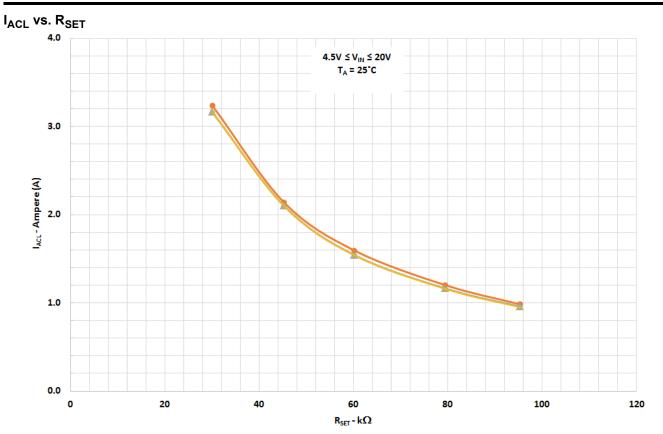
RDS_{ON} vs. Temperature and V_{IN}



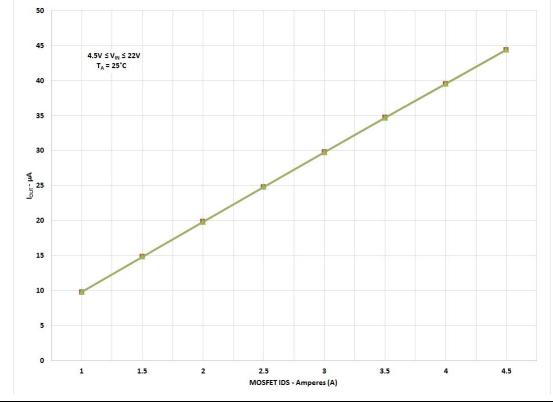








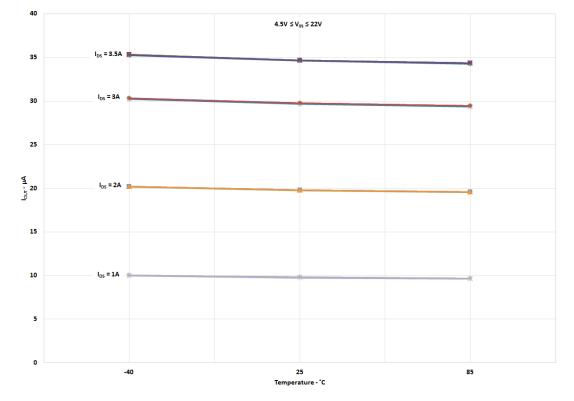




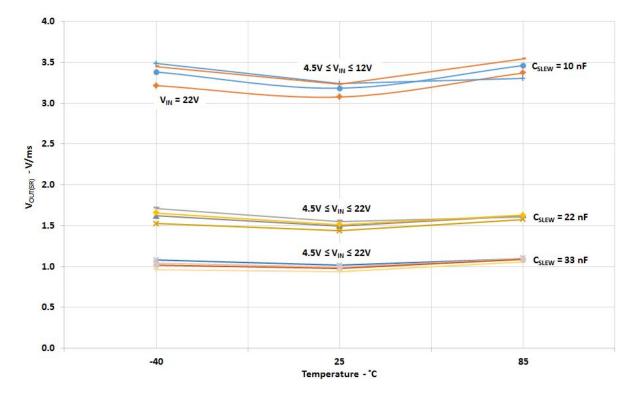
000-0059H1005-102



I_{OUT} vs. Temperature and MOSFET IDS



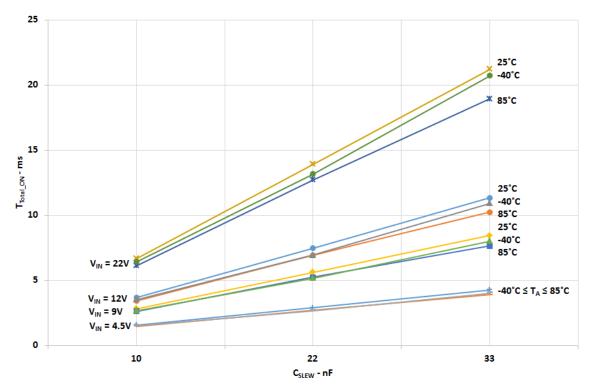
V_{OUT} Slew Rate vs. Temperature, V_{IN}, and C_{SLEW}



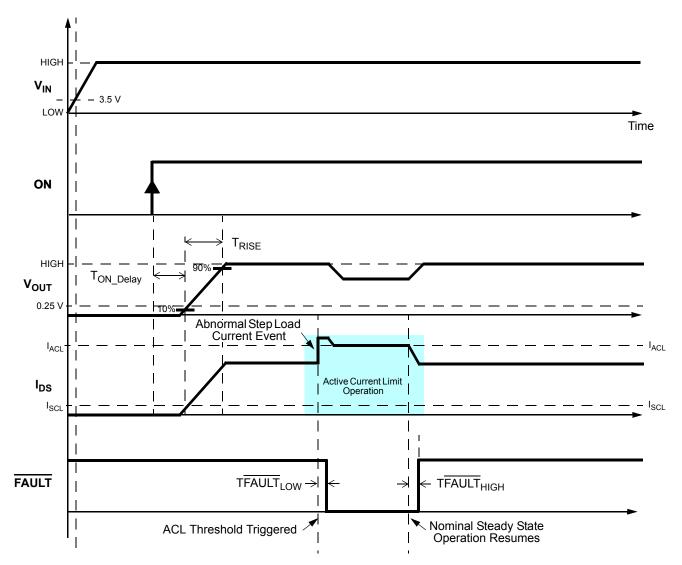


SLG59H1005V



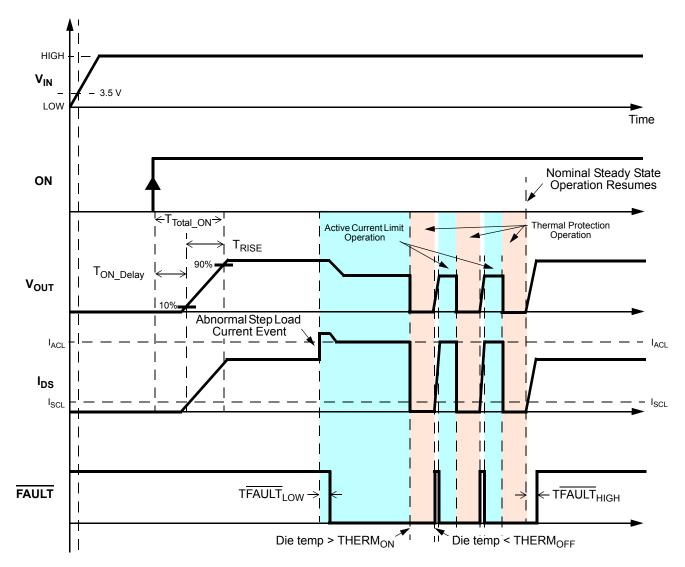






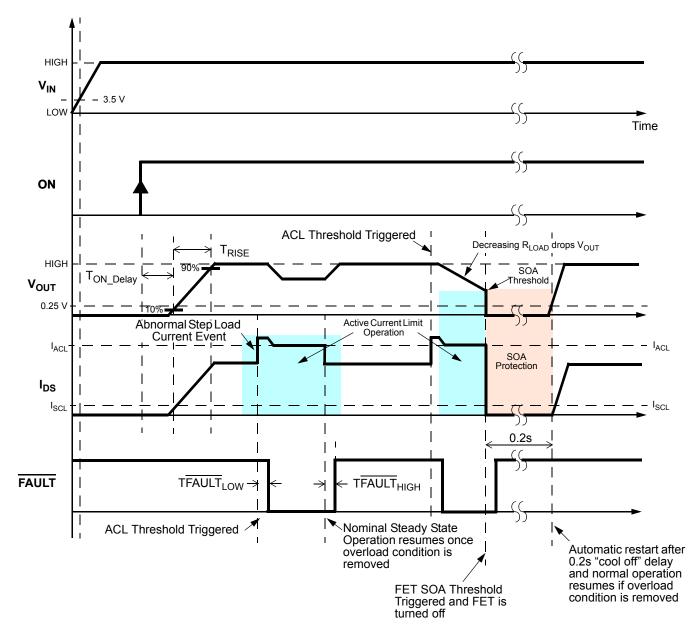
Timing Diagram - Basic Operation including Active Current Limit Protection





Timing Diagram - Active Current Limit & Thermal Protection Operation





Timing Diagram - Basic Operation including Active Current + Internal FET SOA Protection



Applications Information

HFET1 Safe Operating Area Explained

Silego's HFET1 integrated power controllers incorporate a number of internal protection features that prevents them from damaging themselves or any other circuit or subcircuit downstream of them. One particular protection feature is their Safe Operation Area (SOA) protection. SOA protection is automatically activated under overpower and, in some cases, under overcurrent conditions. Overpower SOA is activated if package power dissipation exceeds an internal 5W threshold longer than 2.5 ms. HFET1 devices will quickly switch off (open circuit) upon overpower detection and automatically resume (close) nominal operation once overpower condition no longer exists.

One possible way to have an overpower condition trigger SOA protection is when HFET1 products are enabled into heavy output resistive loads and/or into large load capacitors. It is under these conditions to follow carefully the "Safe Start-up Loading" guidance in the Applications section of the datasheet. During an overcurrent condition, HFET1 devices will try to limit the output current to the level set by the external R_{SET} resistor. Limiting the output current, however, causes an increased voltage drop across the FET's channel because the FET's RDS_{ON} increased as well. Since the FET's RDS_{ON} is larger, package power dissipation also increases. If the resultant increase in package power dissipation is higher/equal than 5 W for longer than 2.5 ms, internal SOA protection will be triggered and the FET will open circuit (switch off). Every time SOA protection is triggered, all HFET1 devices will automatically attempt to resume nominal operation after 160 ms.

Safe Start-up Condition

SLG59H1005V has built-in protection to prevent over-heating during start-up into a heavy load. Overloading the VOUT pin with a capacitor and a resistor may result in non-monotonic V_{OUT} ramping. In general, under light loading on V_{OUT} , V_{OUT} ramping can be controlled with C_{SLEW} value. The following equation serves as a guide:

$$C_{SLEW} = \frac{T_{RISE}}{V_{IN}} \times 5 \,\mu A \times \frac{20}{3}$$

where T_{RISE} = Total rise time from 10% V_{OUT} to 90% V_{OUT} V_{IN} = Input Voltage C_{SLEW} = Capacitor value for CAP pin

When capacitor and resistor loading on V_{OUT} during start up, the following tables will ensure V_{OUT} ramping is monotonic without triggering internal protection:

	Safe Start-up Loading for V _{IN} = 22 V (Monotonic Ramp)								
Slew Rate (V/ms)	C _{SLEW} (nF) ³	C _{LOAD} (μF)	R_{LOAD} (Ω)						
0.5	66.7	500	80						
1.0	33.3	250	80						
1.5	22.2	160	80						
2.0	16.7	120	80						
2.5	13.3	100	80						



	Safe Start-up Loading for V _{IN} = 12 V (Monotonic Ramp)								
Slew Rate (V/ms)	C _{SLEW} (nF) ³	C _{LOAD} (μF)	R_{LOAD} (Ω)						
1	33.3	500	20						
2	16.7	250	20						
3	11.1	160	20						
4	8.3	120	20						
5	6.7	100	20						

Note 3: Select the closest-value tolerance capacitor.

Setting the SLG59H1005V's Active Current Limit

R _{SET} (kΩ)	Active Current Limit (A) ⁴
95	1
45	2
30	3

Note 4: Active Current Limit accuracy is ±15% over voltage range and over temperature range.

Setting the SLG59H1005V's Input Overvoltage Lockout Threshold

As shown in the table below, SEL[1,0] selects the V_{IN} overvoltage threshold at which the SLG59H1005V's internal state machine will turn OFF (open circuit) the power MOSFET if V_{IN} exceeds the selected threshold.

SEL1	SEL0	V _{IN(OVLO)} (Тур)
0	0	6
0	1	10.8
1	0	14.4
1	1	24

For example, SEL[1,1] would be the most appropriate setting for applications where the steady-state V_{IN} can extend up to 20V without causing any damage to the SLG59H1005V since the IC is 29-V tolerant.

With an activated SLG59H1005V (ON=HIGH) and at any time V_{IN} crosses the programmed V_{IN} overvoltage threshold, the state machine opens the power switch and asserts the FAULT pin within TFAULT_{LOW}.

In applications with a deactivated or inactive SLG59H1005V ($V_{IN} > V_{IN(OVLO)}$ and ON=LOW) and if the applied V_{IN} is higher than the programmed $V_{IN(OVLO)}$ threshold, the SLG59H1005V's state machine will keep the power switch open circuited if the ON pin is toggled LOW-to-HIGH. In these cases, the FAULT pin will also be asserted within TFAULT_{LOW} and will remain asserted until VIN resumes nominal, steady-state operation.

In all cases, the SLG59H1005V's V_{IN} undervoltage lockout threshold is fixed at $V_{IN(UVLO)}$.



Power Dissipation

The junction temperature of the SLG59H1005V depends on different factors such as board layout, ambient temperature, and other environmental factors. The primary contributor to the increase in the junction temperature of the SLG59H1005V is the power dissipation of its power MOSFET. Its power dissipation and the junction temperature in nominal operating mode can be calculated using the following equations:

$$PD = RDS_{ON} \times I_{DS}^{2}$$

where:

 $\label{eq:pd} \begin{array}{l} \mathsf{PD} = \mathsf{Power} \mbox{ dissipation, in Watts (W)} \\ \mathsf{RDS}_{\mathsf{ON}} = \mathsf{Power} \mbox{ MOSFET ON resistance, in Ohms } (\Omega) \\ \mathsf{I}_{\mathsf{DS}} = \mathsf{Output} \mbox{ current, in Amps } (\mathsf{A}) \\ \mbox{ and } \end{array}$

$$T_J = PD \times \theta_{JA} + T_A$$

where:

 T_J = Junction temperature, in Celsius degrees (°C) θ_{JA} = Package thermal resistance, in Celsius degrees per Watt (°C/W) T_A = Ambient temperature, in Celsius degrees (°C)

In current-limit mode, the SLG59H1005V's power dissipation can be calculated by taking into account the voltage drop across the power switch (V_{IN} - V_{OUT}) and the magnitude of the output current in current-limit mode (I_{ACL}):

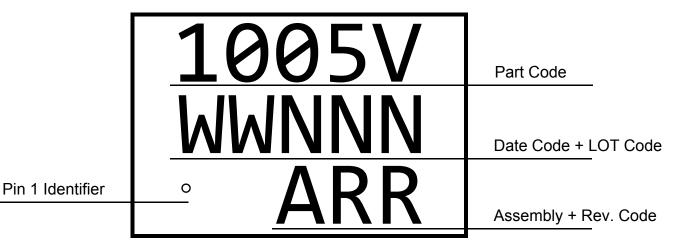
$$\label{eq:pd} \begin{split} \mathsf{PD} &= (\mathsf{V}_{\mathsf{IN}}\text{-}\mathsf{V}_{\mathsf{OUT}}) \times \mathsf{I}_{\mathsf{ACL}} \text{ or} \\ \mathsf{PD} &= (\mathsf{V}_{\mathsf{IN}} - (\mathsf{R}_{\mathsf{LOAD}} \times \mathsf{I}_{\mathsf{ACL}})) \times \mathsf{I}_{\mathsf{ACL}} \end{split}$$

where:

 $\begin{array}{l} \mathsf{PD} = \mathsf{Power dissipation, in Watts} \ (\mathsf{W}) \\ \mathsf{V}_{\mathsf{IN}} = \mathsf{Input Voltage, in Volts} \ (\mathsf{V}) \\ \mathsf{R}_{\mathsf{LOAD}} = \mathsf{Load Resistance, in Ohms} \ (\Omega) \\ \mathsf{I}_{\mathsf{ACL}} = \mathsf{Output limited current, in Amps} \ (\mathsf{A}) \\ \mathsf{V}_{\mathsf{OUT}} = \mathsf{R}_{\mathsf{LOAD}} \times \mathsf{I}_{\mathsf{ACL}} \end{array}$



Package Top Marking System Definition

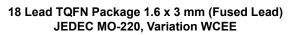


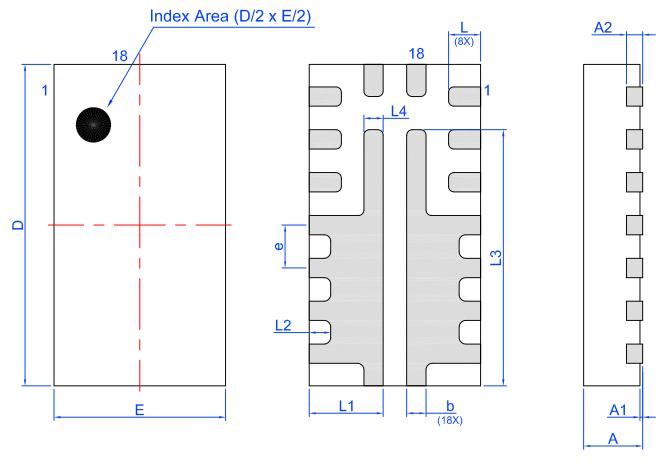
1005V - Part ID Field WW - Date Code Field¹ NNN - Lot Traceability Code Field¹ A - Assembly Site Code Field² RR - Part Revision Code Field²

Note 1: Each character in code field can be alphanumeric A-Z and 0-9 Note 2: Character in code field can be alphabetic A-Z



Package Drawing and Dimensions





Top View

BTM View

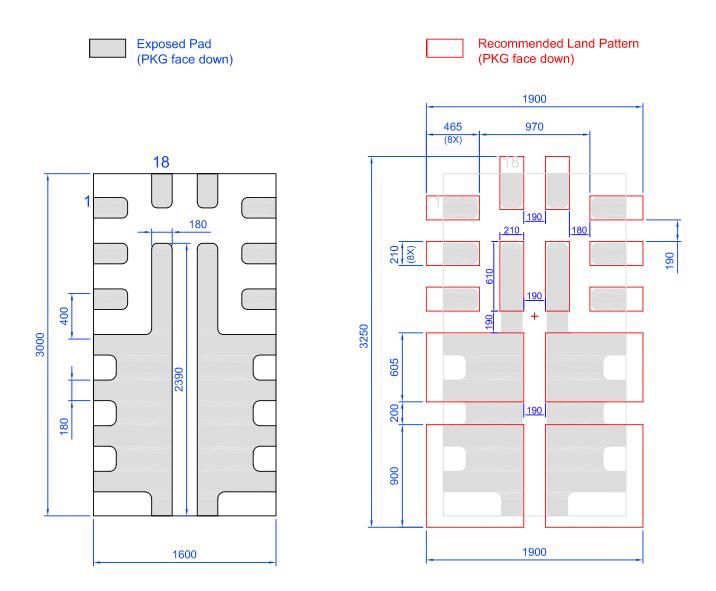
Side View

Unit: mm

Onit. mi	onit. min										
Symbol	Min	Nom.	Max	Symbol	Min	Nom.	Max				
A	0.50	0.55	0.60	D	2.95	3.00	3.05				
A1	0.005	_	0.05	E	1.55	1.60	1.65				
A2	0.10	0.15	0.20	L	0.25	0.30	0.35				
b	0.13	0.18	0.23	L1	0.64	0.69	0.74				
е	(0.40 BSC	, ,	L2	0.15	0.20	0.25				
L3	2.34	2.39	2.44	L4	0.13	0.18	0.23				



SLG59H1005V 18-pin STQFN PCB Landing Pattern



Note: All dimensions shown in micrometers (µm)

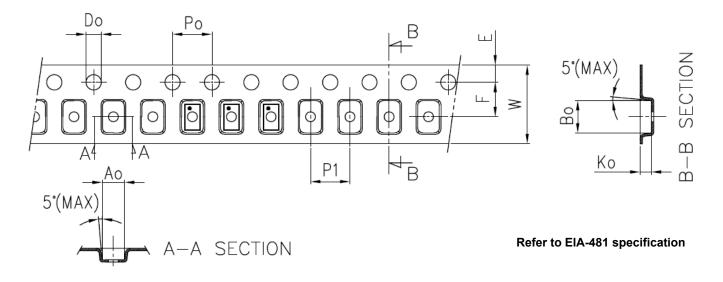


Tape and Reel Specifications

Package # of Type Pins	#	Nominal	Мах	Units	Reel &	Leade	r (min)	Trailer	' (min)	Таре	Part
	# of Pins	Package Size	per Reel	per Box	Hub Size [mm]	Pockets	Length [mm]	Pockets	Length [mm]	Width [mm]	Pitch [mm]
STQFN 18L 0.4P FC Green	18	1.6 x 3 x 0.55	3,000	3,000	178 / 60	100	400	100	400	8	4

Carrier Tape Drawing and Dimensions

Package Type	PocketBTM Length A0	PocketBTM Width B0	Pocket Depth K0	Index Hole Pitch P0	Pocket Pitch P1	Index Hole Diameter D0	Index Hole to Tape Edge E		Tape Width W
STQFN 18L 0.4P FC Green	-	3.18	0.76	4	4	1.5	1.75	3.5	8



Recommended Reflow Soldering Profile

Please see IPC/JEDEC J-STD-020: latest revision for reflow profile based on package volume of 2.64 mm³ (nominal). More information can be found at www.jedec.org.



Revision History

Date	Version	Change	
4/4/2017	1.02	Updated Block Diagram Updated Charts Updated SOA operation Timing Diagrams	
3/21/2017	1.01	Updated Features	
2/24/2017	1.00	Production Release	